

**Search Notes**

Application/Control No.

10/651,110

Examiner

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Applicant(s)/Patent under  
Reexamination

QIAN ET AL.

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner
382	253	3/1/2007	YG

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
382	253	3/1/2007	YG

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR) - See search history printout	3/1/2007	YG
IEEE Xplore - See search session history printout	3/1/2007	YG